

QUAD 2 CHANNEL MULTIPLEXER

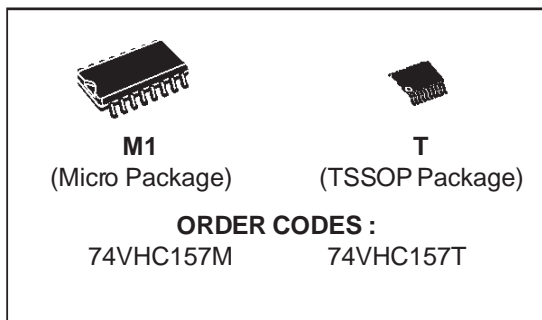
- HIGH SPEED: $t_{PD} = 4.1 \text{ ns}$ (TYP.) at $V_{CC} = 5V$
- LOW POWER DISSIPATION:
 $I_{CC} = 4 \mu\text{A}$ (MAX.) at $T_A = 25^\circ\text{C}$
- HIGH NOISE IMMUNITY:
 $V_{NIH} = V_{NIL} = 28\% V_{CC}$ (MIN.)
- POWER DOWN PROTECTION ON INPUTS
- SYMMETRICAL OUTPUT IMPEDANCE:
 $|I_{OH}| = I_{OL} = 8 \text{ mA}$ (MIN)
- BALANCED PROPAGATION DELAYS:
 $t_{PLH} \cong t_{PHL}$
- OPERATING VOLTAGE RANGE:
 V_{CC} (OPR) = 2V to 5.5V
- PIN AND FUNCTION COMPATIBLE WITH 74 SERIES 157
- IMPROVED LATCH-UP IMMUNITY
- LOW NOISE: $V_{OLP} = 0.8V$ (Max.)

DESCRIPTION

The 74VHC157 is an high-speed CMOS QUAD 2-CHANNEL MULTIPLEXER fabricated with sub-micron silicon gate and double-layer metal wiring C²MOS technology.

It consists of four 2-input digital multiplexers with common select and strobe inputs. It is a

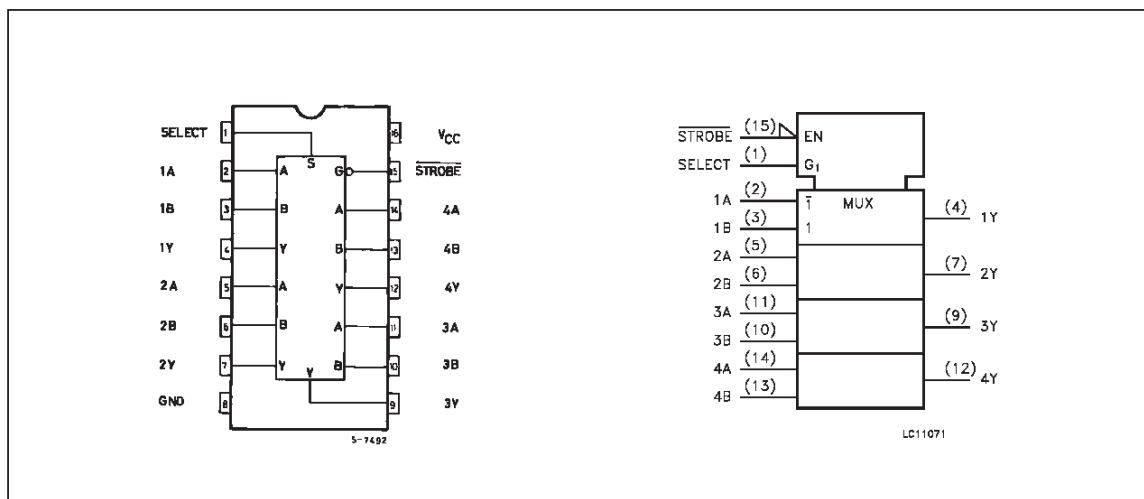
PRELIMINARY DATA



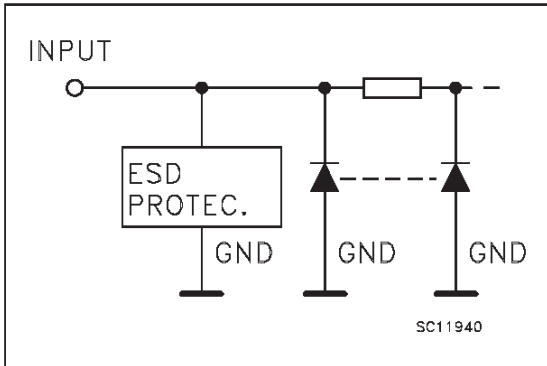
non-inverting multiplexer. When the $\overline{\text{STROBE}}$ input is held high, selection of data is inhibited and all the outputs become low. The SELECT decoding determines whether the A or B inputs get routed to their corresponding Y outputs.

Power down protection is provided on all inputs and 0 to 7V can be accepted on inputs with no regard to the supply voltage. This device can be used to interface 5V to 3V. All inputs and outputs are equipped with protection circuits against static discharge, giving them 2KV ESD immunity and transient excess voltage.

PIN CONNECTION AND IEC LOGIC SYMBOLS



INPUT EQUIVALENT CIRCUIT



PIN DESCRIPTION

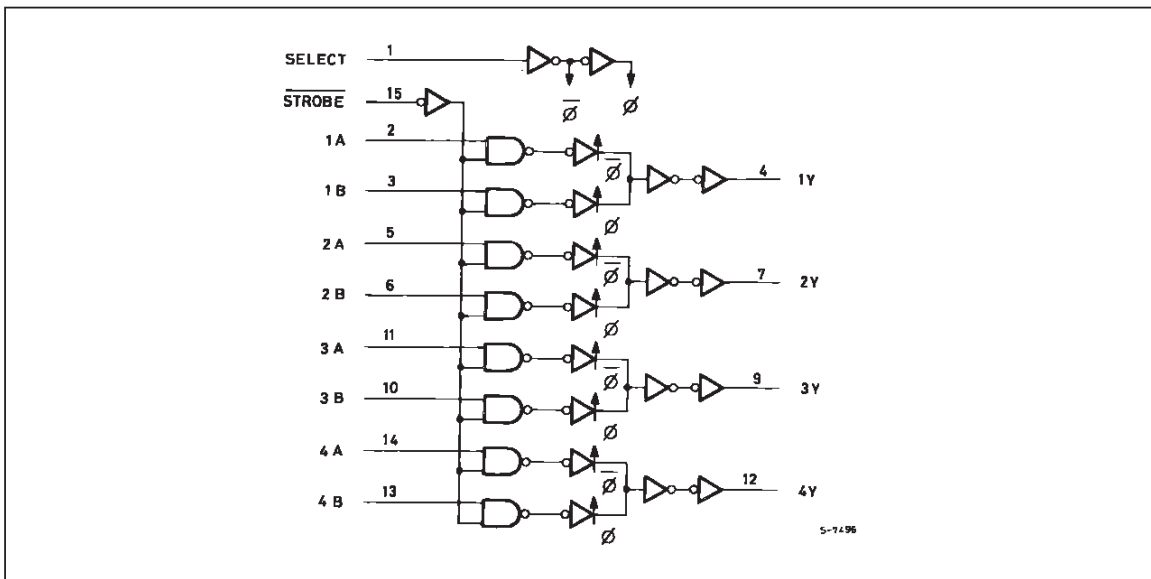
PIN No	SYMBOL	NAME AND FUNCTION
1	SELECT	Common Data Select Input
2, 5, 11, 14	1A to 4A	Data Inputs From Source A
3, 6, 10, 13	1B to 4B	Data Inputs From Source B
4, 7, 9, 12	1Y to 4Y	Multiplexer Outputs
15	$\overline{\text{STROBE}}$	Strobe Input
8	GND	Ground (0V)
16	V _{CC}	Positive Supply Voltage

TRUTH TABLE

INPUT				OUTPUT
$\overline{\text{STROBE}}$	SELECT	A	B	Y
H	X	X	X	L
L	L	L	X	L
L	L	H	X	H
L	H	X	L	L
L	H	X	H	H

X: "H" or "L"

LOGIC DIAGRAM



ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V_{CC}	Supply Voltage	-0.5 to +7.0	V
V_I	DC Input Voltage	-0.5 to +7.0	V
V_O	DC Output Voltage	-0.5 to $V_{CC} + 0.5$	V
I_{IK}	DC Input Diode Current	-20	mA
I_{OK}	DC Output Diode Current	± 20	mA
I_O	DC Output Current	± 25	mA
I_{CC} or I_{GND}	DC V_{CC} or Ground Current	± 50	mA
T_{stg}	Storage Temperature	-65 to +150	$^{\circ}C$
T_L	Lead Temperature (10 sec)	300	$^{\circ}C$

Absolute Maximum Ratings are those values beyond which damage to the device may occur. Functional operation under these condition is not implied.

RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter	Value	Unit
V_{CC}	Supply Voltage	2.0 to 5.5	V
V_I	Input Voltage	0 to 5.5	V
V_O	Output Voltage	0 to V_{CC}	V
T_{op}	Operating Temperature	-40 to +85	$^{\circ}C$
dt/dv	Input Rise and Fall Time (see note 1) ($V_{CC} = 3.3 \pm 0.3V$) ($V_{CC} = 5.0 \pm 0.5V$)	0 to 100 0 to 20	ns/V ns/V

1) V_{IN} from 30% to 70% of V_{CC}

DC SPECIFICATIONS

Symbol	Parameter	Test Conditions		Value					Unit
				$T_A = 25^{\circ}C$			-40 to $85^{\circ}C$		
				V_{CC} (V)	Min.	Typ.	Max.	Min.	
V_{IH}	High Level Input Voltage	2.0		1.5			1.5		V
		3.0 to 5.5		$0.7V_{CC}$			$0.7V_{CC}$		
V_{IL}	Low Level Input Voltage	2.0				0.5		0.5	V
		3.0 to 5.5				$0.3V_{CC}$		$0.3V_{CC}$	
V_{OH}	High Level Output Voltage	2.0	$I_O = 50 \mu A$	1.9	2.0		1.9		V
		3.0	$I_O = 50 \mu A$	2.9	3.0		2.9		
		4.5	$I_O = 50 \mu A$	4.4	4.5		4.4		
		3.0	$I_O = 4 mA$	2.58			2.48		
		4.5	$I_O = 8 mA$	3.94			3.8		
V_{OL}	Low Level Output Voltage	2.0	$I_O = 50 \mu A$		0.0	0.1		0.1	V
		3.0	$I_O = 50 \mu A$		0.0	0.1		0.1	
		4.5	$I_O = 50 \mu A$		0.0	0.1		0.1	
		3.0	$I_O = 4 mA$			0.36		0.44	
		4.5	$I_O = 8 mA$			0.36		0.44	
I_I	Input Leakage Current	0 to 5.5	$V_I = 5.5V$ or GND			± 0.1		± 1.0	μA
I_{CC}	Quiescent Supply Current	5.5	$V_I = V_{CC}$ or GND			4		40	μA

AC ELECTRICAL CHARACTERISTICS (Input $t_r = t_f = 3$ ns)

Symbol	Parameter	Test Condition		Value					Unit
		V _{CC} (V)	C _L (pF)	T _A = 25 °C			-40 to 85 °C		
				Min.	Typ.	Max.	Min.	Max.	
t _{PLH} t _{PHL}	Propagation Delay Time A, B to Y	3.3 ^(*)	15		6.2	9.7	1.0	11.5	ns
		3.3 ^(*)	50		8.7	13.2	1.0	15.0	
		5.0 ^(**)	15		4.1	6.4	1.0	7.5	
		5.0 ^(**)	50		5.6	8.4	1.0	9.5	
t _{PLH} t _{PHL}	Propagation Delay Time SELECT to Y	3.3 ^(*)	15		8.4	13.2	1.0	15.5	ns
		3.3 ^(*)	50		10.9	16.7	1.0	19.0	
		5.0 ^(**)	15		5.3	8.1	1.0	9.5	
		5.0 ^(**)	50		6.8	10.1	1.0	11.5	
t _{PLH} t _{PHL}	Propagation Delay Time STROBE to Y	3.3 ^(*)	15		8.7	13.6	1.0	16.0	ns
		3.3 ^(*)	50		11.2	17.1	1.0	19.5	
		5.0 ^(**)	15		5.6	8.6	1.0	10.0	
		5.0 ^(**)	50		7.1	10.6	1.0	12.0	

(*) Voltage range is 3.3V ± 0.3V

(**) Voltage range is 5V ± 0.5V

CAPACITIVE CHARACTERISTICS

Symbol	Parameter	Test Conditions	Value					Unit
			T _A = 25 °C			-40 to 85 °C		
			Min.	Typ.	Max.	Min.	Max.	
C _{IN}	Input Capacitance			4	10		10	pF
C _{PD}	Power Dissipation Capacitance (note 1)			20				pF

1) C_{PD} is defined as the value of the IC's internal equivalent capacitance which is calculated from the operating current consumption without load. (Refer to Test Circuit). Average operating current can be obtained by the following equation. I_{CC(OPR)} = C_{PD} • V_{CC} • f_{IN} + I_{CC}/4 (per Channel)

DYNAMIC SWITCHING CHARACTERISTICS

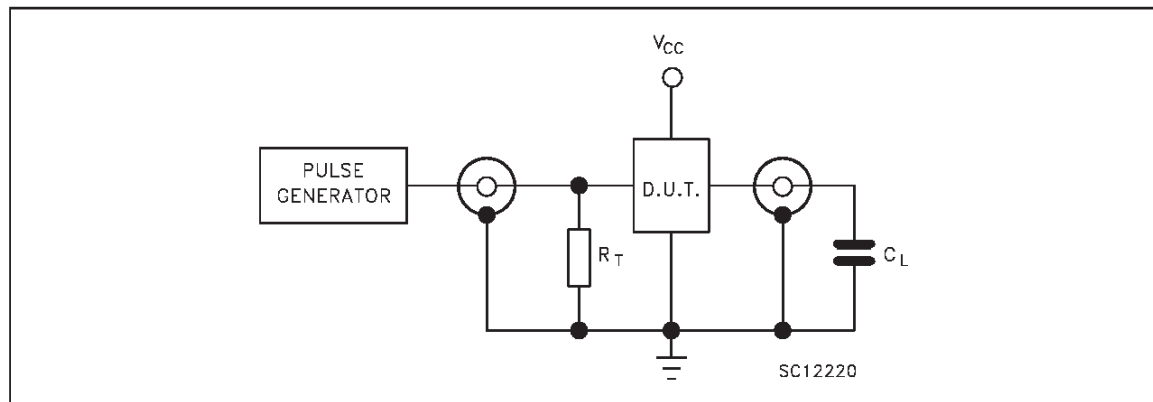
Symbol	Parameter	Test Conditions		Value					Unit
		V _{CC} (V)	C _L = 50 pF	T _A = 25 °C			-40 to 85 °C		
				Min.	Typ.	Max.	Min.	Max.	
V _{OLP}	Dynamic Low Voltage Quiet Output (note 1, 2)	5.0	C _L = 50 pF		0.3	0.8			V
V _{OLV}				-0.8	-0.3				
V _{IHD}	Dynamic High Voltage Input (note 1, 3)	5.0		3.5					
V _{ILD}	Dynamic Low Voltage Input (note 1, 3)	5.0				1.5			

1) Worst case package.

2) Max number of outputs defined as (n). Data inputs are driven 0V to 5.0V, (n-1) outputs switching and one output at GND.

3) Max number of data inputs (n) switching. (n-1) switching 0V to 5.0V. Inputs under test switching: 5.0V to threshold (V_{ILD}), 0V to threshold (V_{IHD}), f=1MHz.

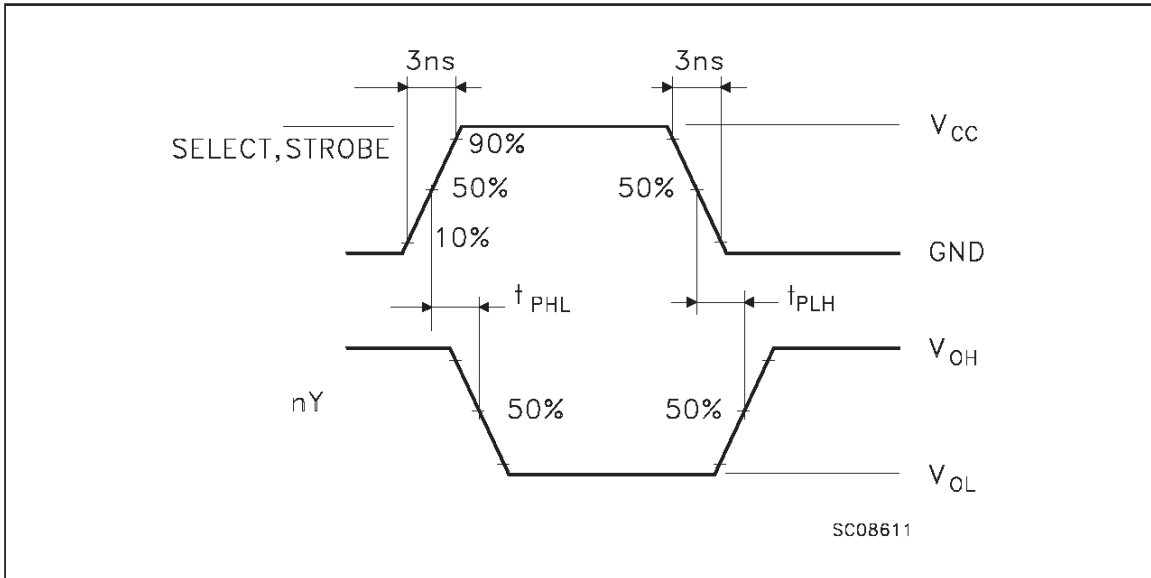
TEST CIRCUIT



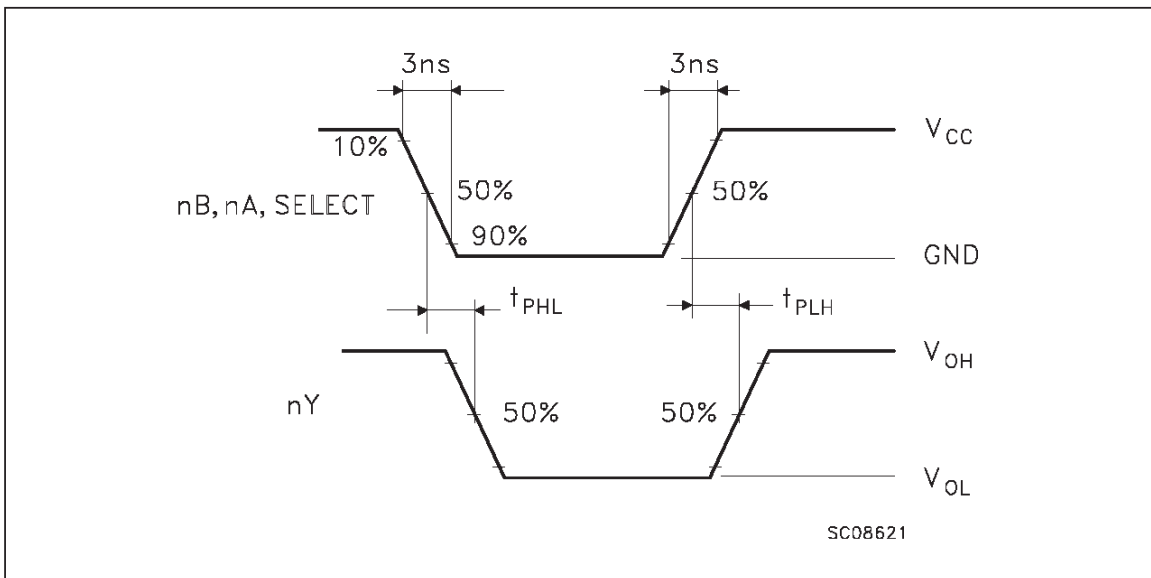
C_L = 15/50 pF or equivalent (includes jig and probe capacitance)

R_T = Z_{OUT} of pulse generator (typically 50Ω)

WAVEFORM 1: PROPAGATION DELAYS FOR INVERTING CONDITIONS

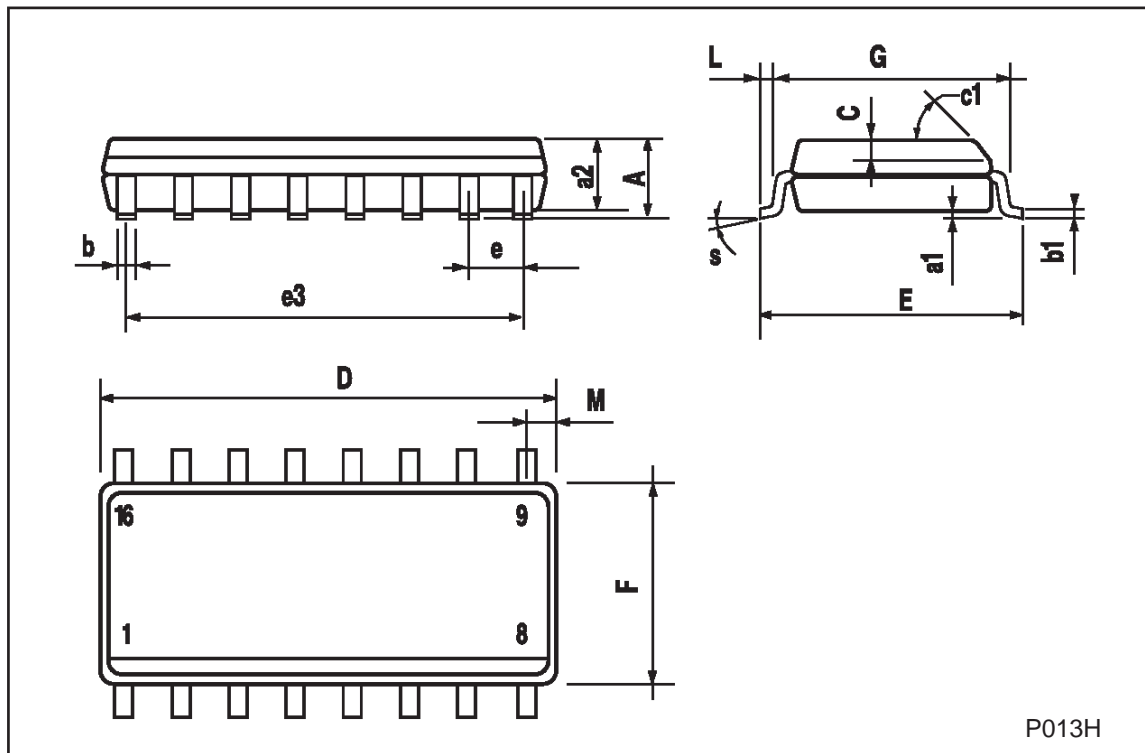


WAVEFORM 2: PROPAGATION DELAYS FOR NON-INVERTING CONDITIONS



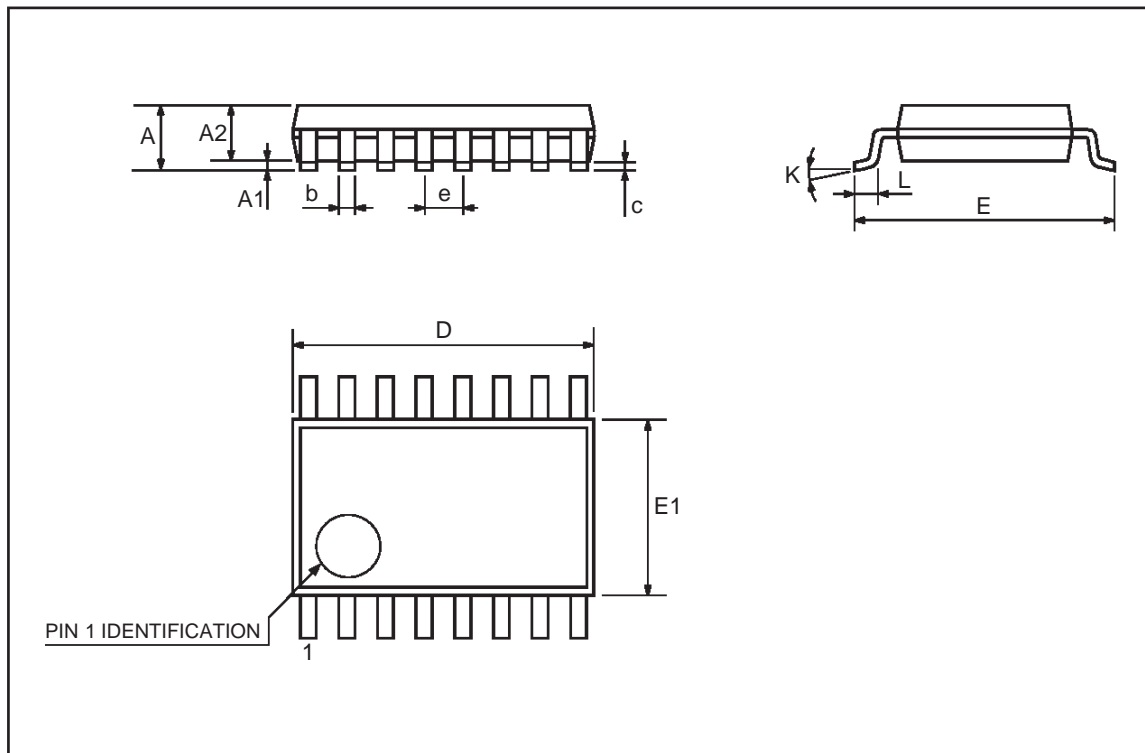
SO-16 MECHANICAL DATA

DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A			1.75			0.068
a1	0.1		0.2	0.004		0.007
a2			1.65			0.064
b	0.35		0.46	0.013		0.018
b1	0.19		0.25	0.007		0.010
C		0.5			0.019	
c1	45 (typ.)					
D	9.8		10	0.385		0.393
E	5.8		6.2	0.228		0.244
e		1.27			0.050	
e3		8.89			0.350	
F	3.8		4.0	0.149		0.157
G	4.6		5.3	0.181		0.208
L	0.5		1.27	0.019		0.050
M			0.62			0.024
S	8 (max.)					



TSSOP16 MECHANICAL DATA

DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A			1.1			0.433
A1	0.05	0.10	0.15	0.002	0.004	0.006
A2	0.85	0.9	0.95	0.335	0.354	0.374
b	0.19		0.30	0.0075		0.0118
c	0.09		0.20	0.0035		0.0079
D	4.9	5	5.1	0.193	0.197	0.201
E	6.25	6.4	6.5	0.246	0.252	0.256
E1	4.3	4.4	4.48	0.169	0.173	0.176
e		0.65 BSC			0.0256 BSC	
K	0°	4°	8°	0°	4°	8°
L	0.50	0.60	0.70	0.020	0.024	0.028



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